

[WCET Analysis Methods: Pitfalls and Challenges on their Trustworthiness](#)

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Authors: [Abella, Jaume](#) / [Hernández, Carles](#) / [Quinones, Eduardo](#) / [Cazorla, Francisco](#) / [Conmy, Philippa](#) / [Azkarate-askasua, Mikel](#) / [Perez, Jon](#) / [Mezzetti, Enrico](#) / [Vardanega, Tullio](#)

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Barcelona Supercomputing Center - Centro Nacional de Supercomputación

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